


<p style="text-align: center;">Search Notes</p> 	<p>Application/Control No.</p> <p>10688316</p>	<p>Applicant(s)/Patent Under Reexamination</p> <p>LANDRAM ET AL.</p>
	<p>Examiner</p> <p>DJENANE M BAYARD</p>	<p>Art Unit</p> <p>2444</p>

SEARCHED

Class	Subclass	Date	Examiner
709	217, 216, 220, 218	10/10/09	db
710	104	10/10/09	db
709	217, 216, 220, 218	7/16/10	db
709	216, 217, 218, 220	9/20/10	db
709	216, 217, 218, 220	5/09/11	db

SEARCH NOTES

Search Notes	Date	Examiner
east	10/10/09	db
East	7/16/10	db
Double Patenting Search	7/16/10	db
NPL Google Search	7/16/10	db
East	9/20/10	db
Double Patenting Search	9/20/10	db
NPL Google Search	9/20/10	db
East	5/10/11	dv

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
709	216, 217, 218, 220	7/16/10	db

/D. M. B./
Primary Examiner.Art Unit 2444